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4-Mbit (512K words × 8-bit) Static RAM

Features

- High speed □ t_{AA} = 10 ns
- Low active and standby currents □ Active current: I_{CC} = 38 mA typical
 - ☐ Standby current: I_{SB2} = 6 mA typical
- Operating voltage range: 1.65 V to 2.2 V, 2.2 V to 3.6 V, and 4.5 V to 5.5 V
- 1.0 V data retention
- TTL-compatible inputs and outputs
- Pb-free 36-pin SOJ and 44-pin TSOP II packages

Functional Description

CY7C1049GN is a high-performance CMOS fast static RAM device organized as 512K words by 8-bits.

Data writes are performed by asserting the Chip Enable (CE) and Write Enable (WE) inputs LOW, while providing the data on I/O₀ through I/O₇ and address on A_0 through A_{18} pins.

Data reads are performed by asserting the Chip Enable (CE) and Output Enable (OE) inputs LOW and providing the required address on the address lines. Read data is accessible on the I/O lines (I/O_0 through I/O_7).

All I/Os (I/O₀ through I/O₇) are placed in a high-impedance state during the following events:

- The device is deselected (CE HIGH)
- The control signal OE is de-asserted

The logic block diagram is on page 2.

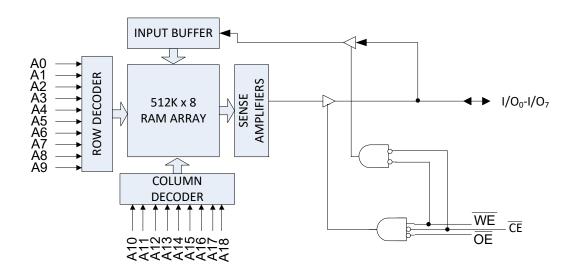
Product Portfolio

				Cmand			Power Di	ssipation	
Product	Range	Speed (ns)		Operating I _{CC} , (mA)		Standby	L (mΔ)		
Floudet	Kange	V _{CC} Range (V)	10/15	f = f _{max}		Standby, I _{SB2} (mA			
			10,10	Typ ^[1]	Max	Typ ^[1]	Max		
CY7C1049GN18	Industrial	1.65 V-2.2 V	15	_	40	6	8		
CY7C1049GN30		2.2 V-3.6 V	10	38	45				
CY7C1049GN		4.5 V–5.5 V	10	38	45				

Typical values are included only for reference and are not guaranteed or tested. Typical values are measured at V_{CC} = 1.8 V (for a V_{CC} range of 1.65 V–2.2 V), V_{CC} = 3 V (for a V_{CC} range of 2.2 V–3.6 V), and V_{CC} = 5 V (for a V_{CC} range of 4.5 V–5.5 V), T_A = 25 °C.



Logic Block Diagram - CY7C1049GN







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Pin Configurations

Figure 1. 36-pin SOJ pinout [2]

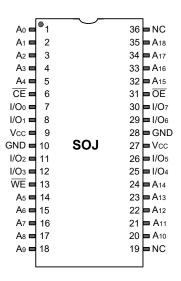
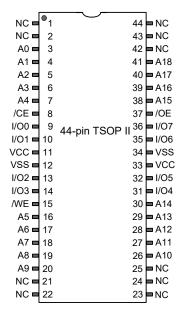


Figure 2. 44-pin TSOP II pinout, Single Chip Enable [2]



Note

2. NC pins are not connected internally to the die.



Maximum Ratings

DC input voltage [3]	0.5 V to V _{CC} + 0.5 V
Current into outputs (in LOW state)	20 mA
Static discharge voltage (MIL-STD-883, Method 3015)	>2001 V
Latch-up current	> 140 mA

Operating Range

G	rade	Ambient Temperature	V _{CC}
Ind	ustrial	–40 °C to +85 °C	1.65 V to 2.2 V, 2.2 V to 3.6 V, 4.5 V to 5.5 V

DC Electrical Characteristics

Over the operating range of -40 °C to 85 °C

D	Description		To at Oo in distance	1	0 ns/15 n	s	Unit
Parameter	Desc	ription	Test Conditions	Min	Typ ^[4]	Max	Unit
V _{OH}	Output HIGH	1.65 V to 2.2 V	V _{CC} = Min, I _{OH} = -0.1 mA	1.4	-	_	V
	voltage	2.2 V to 2.7 V	V _{CC} = Min, I _{OH} = -1.0 mA	2	-	_	
		2.7 V to 3.0 V	V _{CC} = Min, I _{OH} = -4.0 mA	2.2	-	_	
		3.0 V to 3.6 V	V _{CC} = Min, I _{OH} = -4.0 mA	2.4	1	_	
		4.5 V to 5.5 V	V _{CC} = Min, I _{OH} = -4.0 mA	2.4	-	_	
		4.5 V to 5.5 V	V _{CC} = Min, I _{OH} = -0.1mA	$V_{CC} - 0.5^{[5]}$	1	_	
V _{OL}	Output LOW	1.65 V to 2.2 V	V _{CC} = Min, I _{OL} = 0.1 mA	_	1	0.2	V
	voltage	2.2 V to 2.7 V	V _{CC} = Min, I _{OL} = 2 mA	_	1	0.4	
		2.7 V to 3.6 V	V _{CC} = Min, I _{OL} = 8 mA	_	-	0.4	
		4.5 V to 5.5 V	V _{CC} = Min, I _{OL} = 8 mA	_	-	0.4	
V _{IH}		1.65 V to 2.2 V	_	1.4	-	$V_{CC} + 0.2^{[3]}$	V
	Input HIGH	2.2 V to 2.7 V	-	2	1	$V_{CC} + 0.3^{[3]}$	
	voltage	2.7 V to 3.6 V	_	2	-	$V_{CC} + 0.3^{[3]}$	
		4.5 V to 5.5 V	_	2	-	$V_{CC} + 0.5^{[3]}$	
V_{IL}		1.65 V to 2.2 V	_	-0.2 ^[3]	_	0.4	V
	Input LOW	2.2 V to 2.7 V	_	-0.3 ^[3]	-	0.6	
	voltage	2.7 V to 3.6 V	_	-0.3 ^[3]	-	0.8	
		4.5 V to 5.5 V	_	-0.5 ^[3]	_	0.8	
I _{IX}	Input leakage cu	urrent	$GND \le V_{IN} \le V_{CC}$	– 1	_	+1	μА
I _{OZ}	Output leakage	current	GND ≤ V _{OUT} ≤ V _{CC} , Output disabled	– 1	-	+1	μА
I _{CC}	Operating suppl	y current	Max V _{CC} , I _{OUT} = 0 mA, f = 100 MHz CMOS levels	_	38	45	mA
			CMOS levels f = 66.7 MHz	-	_	40	
I _{SB1}	Automatic CE power-down current – TTL inputs		$\begin{aligned} &\text{Max V}_{\text{CC}}, \overline{\text{CE}} \geq \text{V}_{\text{IH}}, \\ &\text{V}_{\text{IN}} \geq \text{V}_{\text{IH}} \text{ or V}_{\text{IN}} \leq \text{V}_{\text{IL}}, \text{ f = f}_{\text{MAX}} \end{aligned}$	_	_	15	mA
I _{SB2}	Automatic CE po current – CMOS		$\begin{aligned} &\text{Max V}_{\text{CC}}, \overline{\text{CE}} \geq \text{V}_{\text{CC}} - 0.2 \text{ V,} \\ &\text{V}_{\text{IN}} \geq \text{V}_{\text{CC}} - 0.2 \text{ V or V}_{\text{IN}} \leq 0.2 \text{ V, f} = 0 \end{aligned}$	_	6	8	mA

Notes

- 3. $V_{IL(min)} = -2.0 \text{ V}$ and $V_{IH(max)} = V_{CC} + 2 \text{ V}$ for pulse durations of less than 20 ns.
- 4. Typical values are included for reference only and are not guaranteed or tested. Typical values are measured at V_{CC} = 1.8 V (for V_{CC} range of 1.65 V 2.2 V), V_{CC} = 3 V (for V_{CC} range of 2.2V 3.6 V), and V_{CC} = 5 V (for V_{CC} range of 4.5 V 5.5 V), V_{CC} = 3 V (for V_{CC} range of 2.2V 3.6 V), and V_{CC} = 5 V (for V_{CC} range of 4.5 V 5.5 V), V_{CC} = 3 V (for V_{CC} range of 2.2V 3.6 V), and V_{CC} = 5 V (for V_{CC} range of 4.5 V 5.5 V), V_{CC} = 3 V (for V_{CC} range of 2.2V 3.6 V), and V_{CC} = 5 V (for V_{CC} range of 4.5 V 5.5 V), V_{CC} = 3 V (for V_{CC} range of 2.2V 3.6 V), and V_{CC} = 5 V (for V_{CC} range of 4.5 V 5.5 V), V_{CC} = 3 V (for V_{CC} range of 2.2V 3.6 V), and V_{CC} = 5 V (for V_{CC} range of 4.5 V 5.5 V), V_{CC} = 3 V (for V_{CC} range of 2.2V 3.6 V), and V_{CC} = 5 V (for V_{CC} range of 4.5 V 5.5 V), V_{CC} = 3 V (for V_{CC} range of 2.2V 3.6 V), and V_{CC} = 5 V (for V_{CC} range of 4.5 V 5.5 V), V_{CC} = 6 V (for V_{CC} range of 2.2V 3.6 V), and V_{CC} = 5 V (for V_{CC} range of 4.5 V 5.5 V), V_{CC} = 6 V (for V_{CC} range of 2.2V 3.6 V), and V_{CC} = 6 V (for V_{CC} range of 4.5 V 5.5 V), V_{CC} = 6 V (for V_{CC} range of 4.5 V 5.5 V), V_{CC} = 6 V (for V_{CC} range of 4.5 V 5.5 V), V_{CC} = 6 V (for V_{CC} range of 4.5 V 5.5 V), V_{CC} = 6 V (for V_{CC} range of 4.5 V 6 V 6 V 6 V 7 V
- 5. This parameter is guaranteed by design and not tested.



Capacitance

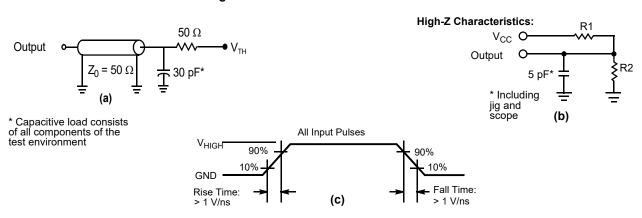
Parameter [6]	eter [6] Description Test Conditions		36-pin SOJ	44-pin TSOP II	Unit
C _{IN}	Input capacitance	T _A = 25 °C, f = 1 MHz,	10	10	pF
C _{OUT}	I/O capacitance	$V_{CC} = V_{CC(typ)}$	10	10	pF

Thermal Resistance

Parameter [6]	Description	Test Conditions	36-pin SOJ	44-pin TSOP II	Unit
Θ_{JA}		Still air, soldered on a 3 × 4.5 inch, four-layer printed circuit board	59.52	68.85	°C/W
$\Theta_{\sf JC}$	Thermal resistance (junction to case)		31.48	15.97	°C/W

AC Test Loads and Waveforms

Figure 3. AC Test Loads and Waveforms [7]



Parameters	1.8 V	3.0 V	5.0 V	Unit
R1	1667	317	317	Ω
R2	1538	351	351	Ω
V _{TH}	0.9	1.5	1.5	V
V _{HIGH}	1.8	3	3	V

Notes

- 6. Tested initially and after any design or process changes that may affect these parameters.
 7. Full-device AC operation assumes a 100-μs ramp time from 0 to V_{CC(min)} and a 100-μs wait time after V_{CC} stabilization.



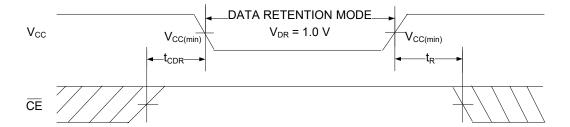
Data Retention Characteristics

Over the operating range of -40 °C to 85 °C

Parameter	Description	Conditions	Min	Max	Unit
V_{DR}	V _{CC} for data retention		1	-	V
I _{CCDR}	Data retention current	$V_{CC} = 1.2 \text{ V}, \overline{CE} \ge V_{CC} - 0.2 \text{ V}^{[8]}, \ V_{IN} \ge V_{CC} - 0.2 \text{ V}, \text{ or } V_{IN} \le 0.2 \text{ V}$	_	8	mA
t _{CDR} ^[9]	Chip deselect to data retention time		0	_	ns
t _R ^[8, 9]	Operation recovery time	V _{CC} ≥ 2.2 V	10	-	ns
		V _{CC} < 2.2 V	15	_	ns

Data Retention Waveform

Figure 4. Data Retention Waveform [8]



- 8. Full-device operation requires linear V_{CC} ramp from V_{DR} to $V_{CC(min)} \ge 100 \,\mu s$ or stable at $V_{CC \, (min)} \ge 100 \,\mu s$.
- 9. These parameters are guaranteed by design.



AC Switching Characteristics

Over the operating range of -40 °C to 85 °C

Parameter [10]	Description	10	ns	15	1114	
Parameter [10]	Description	Min	Max	Min	Max	Unit
Read Cycle		•	•	•	•	
t _{RC}	Read cycle time	10	_	15	_	ns
t _{AA}	Address to data	_	10	_	15	ns
t _{OHA}	Data hold from address change	3	_	3	_	ns
t _{ACE}	CE LOW to data	_	10	_	15	ns
t _{DOE}	OE LOW to data	_	4.5	_	8	ns
t _{LZOE}	OE LOW to low impedance [11]	0	_	0	_	ns
t _{HZOE}	OE HIGH to High-Z [11]	-	5	_	8	ns
t _{LZCE}	CE LOW to low impedance [11]	3	_	3	_	ns
t _{HZCE}	CE HIGH to High-Z [11]	-	5	_	8	ns
t _{PU}	CE LOW to power-up [12, 13]	0	_	0	_	ns
t _{PD}	CE HIGH to power-down [12, 13]	-	10	_	15	ns
Write Cycle [1	3, 14]	•	-	•	•	
t _{WC}	Write cycle time	10	_	15	_	ns
t _{SCE}	CE LOW to write end	7	_	12	_	ns
t _{AW}	Address setup to write end	7	_	12	_	ns
t _{HA}	Address hold from write end	0	_	0	_	ns
t _{SA}	Address setup to write start	0	_	0	_	ns
t _{PWE}	WE pulse width	7	_	12	_	ns
t _{SD}	Data setup to write end	5	_	8	_	ns
t _{HD}	Data hold from write end	0	_	0	_	ns
t _{LZWE}	WE HIGH to low impedance ^[11]	3	_	3	_	ns
t _{HZWE}	WE LOW to High-Z [11]	_	5	_	8	ns

^{10.} Test conditions assume a signal transition time (rise/fall) of 3 ns or less, timing reference levels of 1.5 V (for $V_{CC} \ge 3$ V) and $V_{CC}/2$ (for $V_{CC} < 3$ V), and input pulse levels of 0 to 3 V (for $V_{CC} \ge 3$ V) and 0 to V_{CC} (for $V_{CC} < 3$ V). Test conditions for the read cycle use output loading, as shown in part (a) of Figure 3 on page 6, unless specified otherwise.

^{11.} t_{HZOE}, t_{HZCE}, t_{HZWE}, t_{LZOE}, and t_{LZWE} are specified with a load capacitance of 5 pF, as shown in part (b) of Figure 3 on page 6. Transition is measured ±200 mV from steady state

^{12.} These parameters are guaranteed by design and are not tested.

^{13.} The internal write time of the memory is defined by the overlap of WE = V_{IL}, $\overline{\text{CE}} = \text{V}_{\text{IL}}$. These signals must be LOW to initiate a write, and the HIGH transition of any of these signals can terminate the operation. The input data setup and hold timing should be referenced to the edge of the signal that terminates the write.

14. The minimum write cycle pulse width in Write Cycle No. 2 (WE Controlled, OE LOW) should be equal to sum of t_{DS} and t_{HZWE}.



Switching Waveforms

Figure 5. Read Cycle No. 1 (Address Transition Controlled) [15, 16]

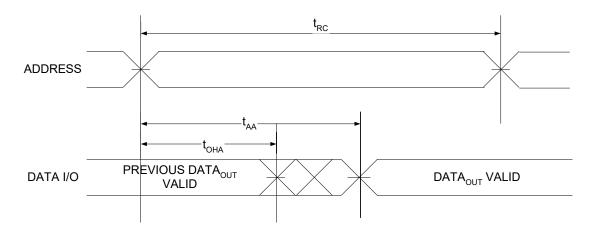
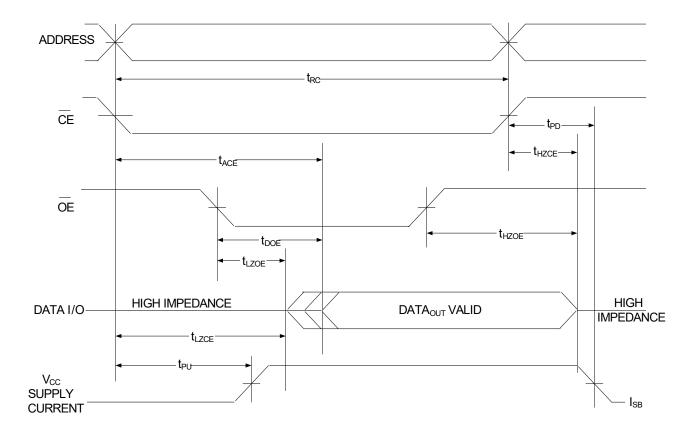


Figure 6. Read Cycle No. 2 (OE Controlled) [15, 16]



Notes
15. WE is HIGH for the read cycle.
16. Address valid prior to or coincident with CE LOW transition.



Switching Waveforms (continued)

Figure 7. Write Cycle No. 1 (CE Controlled) [17, 18]

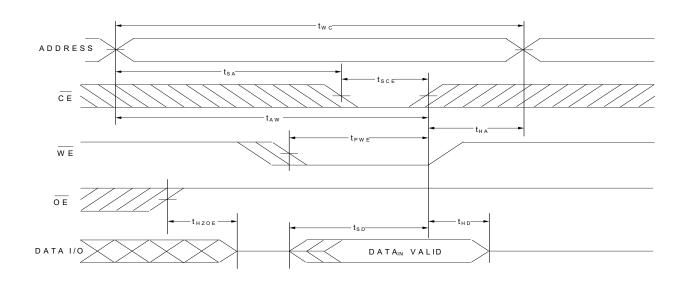
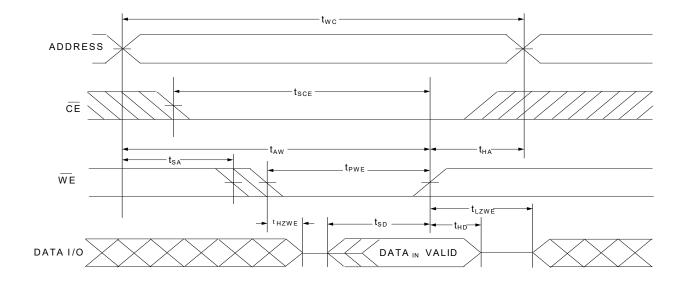


Figure 8. Write Cycle No. 2 (WE Controlled, OE LOW) [17, 18, 19]



Notes

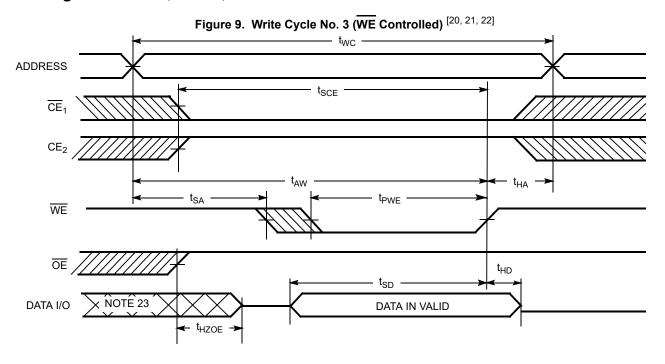
^{17.} The internal write time of the memory is defined by the overlap of WE = V_{|L}, \overline{CE} = V_{|L}. These signals must be LOW to initiate a write, and the HIGH transition of any of these signals can terminate the operation. The input data setup and hold timing should be referenced to the edge of the signal that terminates the write.

18. Data I/O is in HI-Z state if \overline{CE} = V_{|H}, or \overline{OE} = V_{|H}.

^{19.} The minimum write cycle pulse width should be equal to sum of t_{SD} and t_{HZWE}.



Switching Waveforms (continued)



Notes

^{20.} The internal write time of the memory is defined by the overlap of WE = V_{IL}, CE = V_{IL}. These signals must be LOW to initiate a write, and the HIGH transition of any of these signals can terminate the operation. The input data setup and hold timing should be referenced to the edge of the signal that terminates the write.

21. Data I/O is in HI-Z state if CE = V_{IH}, or OE = V_{IH}.

^{22.} Data I/O is high impedance if $\overline{\text{OE}}$ = V_{IH}.

^{23.} During this period the I/Os are in output state. Do not apply input signals.



Truth Table

CE	OE	WE	I/O ₀ –I/O ₇	Mode	Power
Н	X ^[24]	X ^[24]	HI-Z	Power down	Standby (I _{SB})
L	Г	Н	Data out	Read all bits	Active (I _{CC})
L	Х	L	Data in	Write all bits	Active (I _{CC})
L	Н	Н	HI-Z	Selected, outputs disabled	Active (I _{CC})

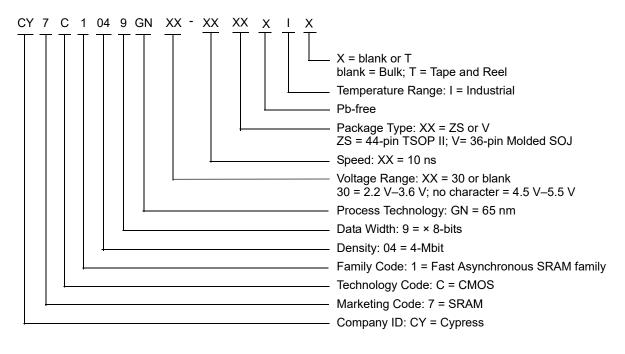
24. The input voltage levels on these pins should be either at $V_{\mbox{\scriptsize IH}}$ or $V_{\mbox{\scriptsize IL}}.$



Ordering Information

Speed (ns)	Voltage Range	Ordering Code	Package Diagram	Package Type (all Pb-free)	Operating Range
10	2.2 V-3.6 V	CY7C1049GN30-10ZSXI	51-85087	44-pin TSOP II	Industrial
		CY7C1049GN30-10ZSXIT	51-85087	44-pin TSOP II, Tape and Reel	
		CY7C1049GN30-10VXI	51-85090	36-pin Molded SOJ	
		CY7C1049GN30-10VXIT	51-85090	36-pin Molded SOJ, Tape and Reel	
	4.5 V-5.5 V	CY7C1049GN-10VXI	51-85090	36-pin Molded SOJ	
		CY7C1049GN-10VXIT	51-85090	36-pin Molded SOJ, Tape and Reel	

Ordering Code Definitions





Package Diagrams

Figure 10. 44-pin TSOP Z44-II Package Outline, 51-85087

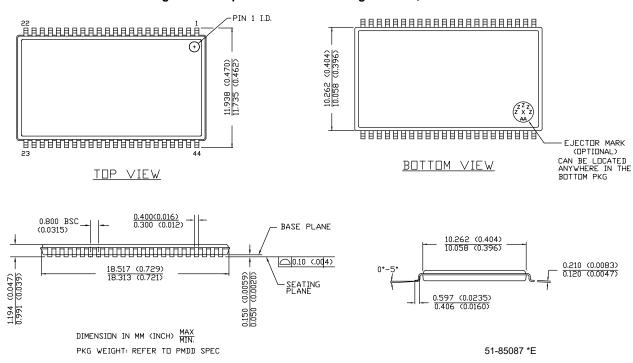
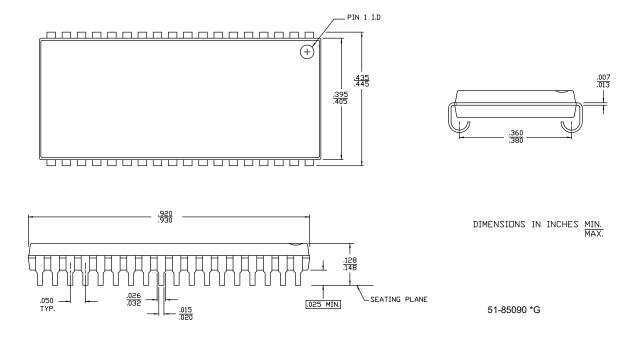


Figure 11. 36-pin SOJ V36.4 (Molded) Package Outline, 51-85090





Acronyms

Acronym	Description		
BHE	byte high enable		
BLE	byte low enable		
CE	chip enable		
CMOS	complementary metal oxide semiconductor		
I/O	input/output		
ŌĒ	output enable		
SRAM	static random access memory		
TSOP	thin small outline package		
TTL	transistor-transistor logic		
VFBGA	very fine-pitch ball grid array		
WE	write enable		

Document Conventions

Units of Measure

Symbol	Unit of Measure			
°C	Degrees Celsius			
MHz	megahertz			
μΑ	microamperes			
μS	microseconds			
mA	milliamperes			
mm	millimeter			
ns	nanoseconds			
Ω	ohms			
%	percent			
pF	picofarads			
V	volts			
W	watts			



Document History Page

Document Document	Oocument Title: CY7C1049GN, 4-Mbit (512K words × 8-bit) Static RAM Oocument Number: 002-10613					
Rev.	ECN No.	Orig. of Change	Submission Date	Description of Change		
**	5074703	NILE	01/06/2016	New data sheet.		
*A	5082587	NILE	01/12/2016	6 Updated Logic Block Diagram – CY7C1049GN. Updated Ordering Information: Updated part numbers.		
*B	5437570	NILE	09/15/2016	Updated DC Electrical Characteristics: Removed details of V_{OH} parameter corresponding to "2.7 V to 3.6 V" and Test Condition " V_{CC} = Min, I_{OH} = -4.0 mA". Added details of V_{OH} parameter corresponding to "2.7 V to 3.0 V" and Test Condition " V_{CC} = Min, I_{OH} = -4.0 mA". Added details of V_{OH} parameter corresponding to "3.0 V to 3.6 V" and Test Condition " V_{CC} = Min, I_{OH} = -4.0 mA". Changed minimum value of V_{IH} parameter corresponding to "4.5 V to 5.5 from 2.2 V to 2 V. Updated Note 3 (Replaced "2 ns" with "20 ns"). Updated Ordering Information: Updated part numbers. Updated to new template.		
*C	5966829	NILE	11/14/2017	Updated Switching Waveforms: Updated Figure 6. Updated Figure 7. Updated Figure 8. Updated Figure 9. Updated to new template. Completing Sunset Review.		

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